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PCN Date: 10/10/2016 Effective Date: 1/13/2017

Title: EFM8SB2 Revision B PCN

### **PCN Type:**

□ Datasheet

#### **PCN Details**

### **Description of Change:**

Silicon Labs is pleased to announce revision B of the EFM8SB2 devices, version 0.5 of the errata, and version 1.2 of the corresponding datasheet for these products.

#### Overview and major changes:

A "Bootloader Signature Byte" has been added to the EFM8SB2 to support a factory programmed bootloader.

- Each device will use the byte immediately before the Lock Byte as a Bootloader Signature Byte to determine if the bootloader is present in flash.
- -Setting the Bootloader Signature Byte to a value of 0xA5 indicates the presence of the bootloader in the system. Any other value in this location indicates that the bootloader is not present in flash.

### Datasheet version 1.2:

- -Added information on the included bootloader described above.
- -All part numbers in the datasheet now reflect the revision change with a 'B'.
- -Added Power-On Reset Threshold and Power-On Reset Delay specifications for a finite Vdd value and delay times.
- -The feature list has been update to include that all pins are now 5V tolerant under bias.
- -Added a section describing the typical connection for debugging EFM8SB2. This includes pin sharing techniques of the C2 interface, refer to section 5.2 of the datasheet for more information.
- -In the introduction section a line was added to mention the reference manual where an individual can find more technical information on registers and blocks.

#### Errata version 0.5:

-Added information on the bootloader described above.

After the effective date of this PCN, Silicon Labs reserves the right to deliver EFM8SB2 Rev B for customers ordering EFM8SB2 Rev A.

#### Reason for Change:

EFM8SB2 datasheet version 1.2 release

EFM8SB2 Revision B release

EFM8SB2 version 0.5 errata



### Impact on Form, Fit, Function, Quality, Reliability:

This change is considered a minor change which does not affect form, fit, function, quality, or reliability.

#### **Product Identification:**

Replacement Part Number	Drop in Compatible Indicator
EFM8SB20F16G-B-QFN24	Yes
EFM8SB20F16G-B-QFN24R	Yes
EFM8SB20F32G-B-QFN24	Yes
EFM8SB20F32G-B-QFN24R	Yes
EFM8SB20F32G-B-QFN32	Yes
EFM8SB20F32G-B-QFN32R	Yes
EFM8SB20F32G-B-QFP32	Yes
EFM8SB20F32G-B-QFP32R	Yes
EFM8SB20F64G-B-QFN24	Yes
EFM8SB20F64G-B-QFN24R	Yes
EFM8SB20F64G-B-QFN32	Yes
EFM8SB20F64G-B-QFN32R	Yes
EFM8SB20F64G-B-QFP32	Yes
EFM8SB20F64G-B-QFP32R	Yes
	EFM8SB20F16G-B-QFN24 EFM8SB20F16G-B-QFN24R EFM8SB20F32G-B-QFN24 EFM8SB20F32G-B-QFN24R EFM8SB20F32G-B-QFN32 EFM8SB20F32G-B-QFN32R EFM8SB20F32G-B-QFP32 EFM8SB20F32G-B-QFP32 EFM8SB20F64G-B-QFN24 EFM8SB20F64G-B-QFN24R EFM8SB20F64G-B-QFN32 EFM8SB20F64G-B-QFN32 EFM8SB20F64G-B-QFN32

Note: The part numbers above include tape and reel variants which are denoted with an "R" at the end of the orderable part number.

Last Date of Unchanged Product: 1/13/2017

#### **Qualification Samples:**

Samples are available now. Please contact your Silicon Labs sales representative to order samples. A list of Silicon Labs sales representatives is available at <a href="https://www.silabs.com">www.silabs.com</a>.



Specific conditions of acceptance of this change will be considered on a case by case basis if written notice is submitted within 30 days of this notice. To request further data or inquire about this notification, please contact your local Silicon Labs sales representative. A list of Silicon Labs sales representatives is available at <a href="https://www.silabs.com">www.silabs.com</a>.

In some cases rejection of a change notice may impact Silicon Labs product pricing, delivery, quality, or reliability.

Customer Early Acceptance Sign Off:

Customers may approve early PCN acceptance by completing the information below:

Early Acceptance:

Date:

Name:

Company:

Email your early Acceptance approval to: <a href="mailto:katherine.haggar@silabs.com">katherine.haggar@silabs.com</a>

Qualification Data:

See below.



## EFM8SB20Fxxx Qualification Report

W7101F1 - Product Qualification Plan and Report Record Rev. G

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			1	Fail/Pass or			
Test Name	Test Condition	Qualification	Start	End	Notes	Summary	Sta tus
Test Group A - A	accelerated Environment Stress	:Tests					
HAST			Q25565	0/80	1		
			Q25562	0/80	1		
			Q25572	0/80	2		
			Q25669	0/80	2		
	JA110		Q25017	0/80	3		
	130°C, 85%RH	3 lots, N⊨>25	Q25183	0/80	3	7 lots	Pass
	Voc=3.6V, 96 hours		Q25536	0/80	3	0/560	
Temp Cycle			Q25560	0/80	1		
			Q25564	0/80	1		
			Q25574	0/80	2		
			Q25665	0/80	2		
	JA104		Q25000	0/80	3		
	Cond C: -65°C to 150°C	3 lots, N⊨>25	Q25185	0/80	3	7 lots	Pass
	500 cycles		Q25534	0/80	3	0/560	
HTSL			Q25566	0/80	1		
			Q25563	0/80	1		
			Q25573	0/80	2		
			Q25663	0/80	2		
	JA103		Q24921	0/80	3		
	150°C, 1000hr	3 lots, N=>25	Q25137	0/80	3	7 lots	Pass
		'	Q25414	0/80	3	0/560	
Unbiased HAST		İ	Q24461	0/80	1		
			Q25571	0/80	1		
			Q25567	0/80	2		
			Q25667	0/80	2		
	JA118		Q24999	0/80	3		
	130°C, 85%RH, 96hr	3 lots, N=>25	Q24184	0/80	3	7 lots	Pass
		' '	Q25535	0/80	3	0/560	



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EFM8SB20Fxxx Rev B, TSMC Fabrication, Unisem/SPIL Assembly except as noted							
Test Group B - Accel	lerated Lifetime Simulation	n Tests - Unisem	Assembly ι	unless noted			
HTOL	JA108		Q25551	0/80			
	125°C, Dynamic	3 lots, N=>77	Q26146	0/80	4	3 lots	Pass
	V∞=3.6V, 1000 hours		Q26266	0/80		0/240	
LTOL	JA108						
	-10°C, Dynamic	1 lot, N⊨>32	Q25548	0/40	4	1 lots	Pass
	V∞=3.6V, 1000 hours					0/40	
ELFR			Q25505	0/500			
			Q26046	0/500			
	JA108		Q26216	0/520			
	125°C, Dynamic	3 lots, N⊨>500	Q32063	0/528		5 lots	Pass
	V∞=3.6V, 48 hours		Q34348	0/500		0/2548	
High Temperature	JESD22-A1117		Q26232	0/40			
Data Retention /	500 cycles @Vcc=1.4V		Q26231	0/40			
Cycling Endurance for NVM	88/130°C for 500 hours	3 lots, N⊨>39	Q26235	0/40		3 lots	Pass
TOT IN WWY						0/120	
Low Temperature	JESD22-A108		Q26233	0/40			
Data Retention /	500 cycles @Vcc=1.4V		Q26230	0/40			
Cycling Endurance	25°C for 500 hours	3 lots, N⊨>38	Q26234	0/40		3 lots	Pass
for NVM						0/120	
Test Group E - Elect							
ESD-HBM	JA114						
		1 lot, N=>3	Q26025				2 kV
555 1111			Q32061				
ESD-AWA	JA115		00/075				205.4
		1 lot, N⊨>3	Q26275				225 V
ESD-CDW	JC101		Q26237				
LJD-CDW	30.101	1 lot, N⊨>3	Q32062				1 kV
		, 1,,0	Q34343				1 1/4
Latch Up			<u></u>				
<b>I</b> '			Q25523	85 C			
	JESD78		Q25524	25 C			
	±200m A	1 lot, N=>6	Q32120	85 C			Pass
			Q32119	25 C			



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EFM8SB20Fxx	x Rev B, TSMC Fabricat	ion, Unisem/S	PIL Asser	mbly excep	t as not	ed	
Supplemental Pa	ckage Qualification Data						
Test Group A - Ad	celerated Environment Stress	s Tests - AŒCL -	QFN				
HAST	JA110		Q29385	0/78			
	130°C, 85%RH	3 lots, N⊨>25	Q29331	0/80		3 lots	Pass
	96hours		Q29336	0/80		0/238	
Temp Cycle	JA104		Q29387	0/77			
	Cond C: -65°C to 150°C	3 lots, N=>25	Q29391	0/77		3 lots	Pass
	500 cycles		Q29395	0/77		0/231	
HTSL	JA103		Q29388	0/77			
	150°C, 1000hr	3 lots, N=>25	Q29392	0/77		3 lots	Pass
			Q29396	0/77		0/231	
Test Group A - Ad	ccelerated Environment Stress	Tests - Unisem	- QFN				
HAST	JA110		Q26130	0/80			
	130°C, 85%RH	3 lots, N=>25	Q29179	0/80		3 lots	Pass
	96hours		Q26439	0/80		0/240	
Temp Cycle	JA104		Q26129	0/80			
	Cond C: -65°C to 150°C	3 lots, N⊨>25	Q26182	0/80		3 lots	Pass
	500 cycles		Q26441	0/100		0/260	
HTSL	JA103		Q26131	0/84			
	150°C, 1000hr	3 lots, N=>25	Q26180	0/85		3 lots	Pass
			Q26440	0/101		0/270	

#### Notes:

- 1. SPIL 32LQFP, Precon MSL3@260C
- 2. SPIL 48TQFP, Precon MSL2@260C
- 3. SPIL 64TQFP, Precon MSL3@260C
- 4. Qualification performed on Carsem 32QFN

	This report applies to the following part numbers:	
EFW85B20F64G-B-QFP32	E FW8SB20F64G- B-QFN24	
EFW8SB20F32G-B-QFP32	E FW85B20F32G- B-QFN24	
EFW8SB20F64G-B-QFN32	E FW8SB20F16G- B-QFN24	
EFW8SB20F32G-B-QFN32		